BS ISO 17470:2014

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Microbeam analysis — Electron probe microanalysis — Guidelines for qualitative point analysis by wavelength dispersive X-ray spectrometry

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National foreword

This British Standard is the UK implementation of ISO 17470:2014. It supersedes BS ISO 17470:2004 which is withdrawn.

The UK participation in its preparation was entrusted to Technical Committee CII/9, Microbeam analysis.

A list of organizations represented on this committee can be obtained on request to its secretary.

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ISBN 978 0 580 84121 7

ICS 71.040.99

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This British Standard was published under the authority of the Standards Policy and Strategy Committee on 31 January 2014.

Amendments issued since publication

Date	Text affected

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INTERNATIONAL STANDARD

ISO 17470

Second edition
2014-01-15

Microbeam analysis — Electron probe microanalysis — Guidelines for qualitative point analysis by wavelength dispersive X-ray spectrometry

Analyse par microfaisceaux — Analyse par microsonde électronique (Microsonde de Castaing) — Lignes directrices pour l'analyse qualitative ponctuelle par spectrométrie de rayons X à dispersion de longueur d'onde (WDX)

Reference number
ISO 17470:2014(E)

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Published in Switzerland

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Foreword

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The committee responsible for this document is ISO/TC 202, *Microbeam analysis*, Subcommittee SC 2, *Electron probe microanalysis*.

This second edition cancels and replaces the first edition (ISO 17470:2004), of which it constitutes a minor revision.

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Introduction

Electron probe microanalysis is used to qualitatively identify the elements present in a specimen on a micrometric scale. It is necessary to specify the measurement conditions and identification method in order to avoid reporting erroneous or inconsistent results.

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